

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/678,045	<b>Applicant(s)/Patent under Reexamination</b>  SHINRIKI ET AL.
<b>Examiner</b>  B. Chen	<b>Art Unit</b>  1762	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner